

Doc.	Title	Vote
6872;	Revision to SEMI PV75-1016, Test Method on Cell Level for	Passed
	Potential-induced-degradation Susceptibility of Solar Cells and Module	
	Encapsulation Materials;	
6977-LI1;	Several sections are re-formatted as to meet the requirement which is	Passed
	specified in section 3.2 of Procedure Manual.;	
6977-LI2;	The document number of several references is updated as well as	Passed
	obsolete and non-essential references are deleted.;	
6994;	Reapproval of SEMI G89-0211 (Reapproved 0318) Specification for	Passed
	Leadframe Strip Size;	
6995;	Reapproval of SEMI G71-0996 (Reapproved 0318) Specification for	Passed
	Barcode Marking of Intermediate Containers for Packaging Materials;	
6996;	Reapproval of SEMI G69-0996 (Reapproved 0318): Test Method for	Passed
	Measurement of Adhesive Strength Between Leadframes and Molding	
	Compounds;	
6997;	Reapproval of SEMI G90-0811 (Reapproved 0318): Specification for	Passed
	300 mm Wafer Coin-Stack Type Shipping Container Used for Test and	
	Packaging Processes;	
6998;	Reapproval of SEMI G66-96 (Reapproved 0318): Test Method for the	Passed
	Measurement of Water Absorption Characteristics for Semiconductor	
	Plastic;	
6999;	Reapproval of SEMI G23-0996 (Reapproved 0318): Test Method of	Passed
	Inductance for Internal Traces of Semiconductor Packages;	
R6831C;	Ratification Ballot, Revision to SEMI S1-1015 Safety Guideline for	Passed
	Equipment Safety Labels;	
R7002	Ratification Ballot, Revision to SEMI E132-0922 Specification for	Passed
	Equipment Client Authentication and Authorization and SEMI E132.2-	
	0422e Specification for Protocol Buffers for Equipment Client	
	Authentication and Authorization (ECA)	

Line Item (LI)

For more information, please contact the SEMI Standards Engineer/Coordinator. (<u>http://www.semi.org/standards/contacts</u>) nearest you.

KN V1 July 7, 2023